

CS 5122-00

VLSI Design for

Manufacturability

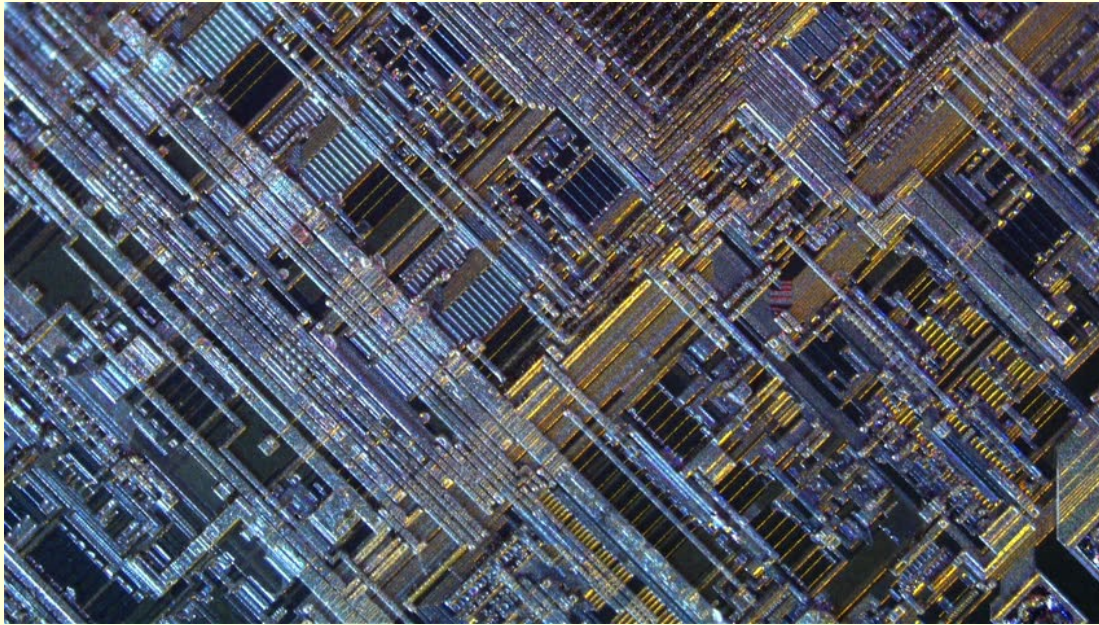
麥偉基

Wai-Kei Mak

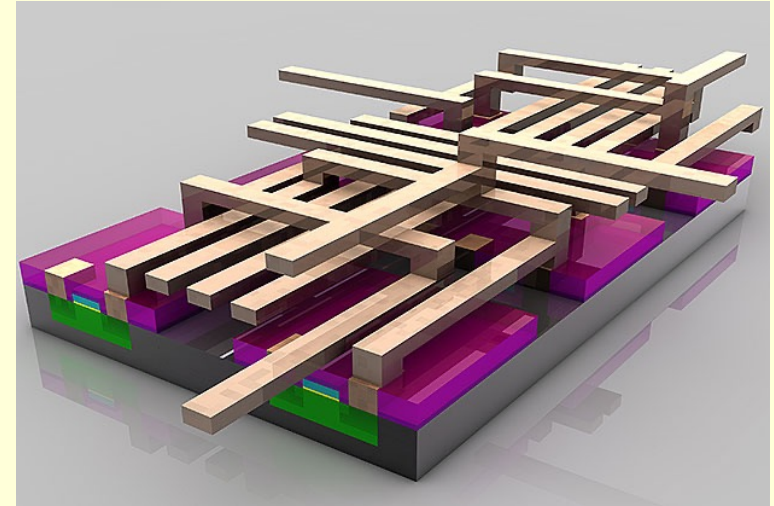
What is VLSI DFM?



Inside of a Silicon Chip

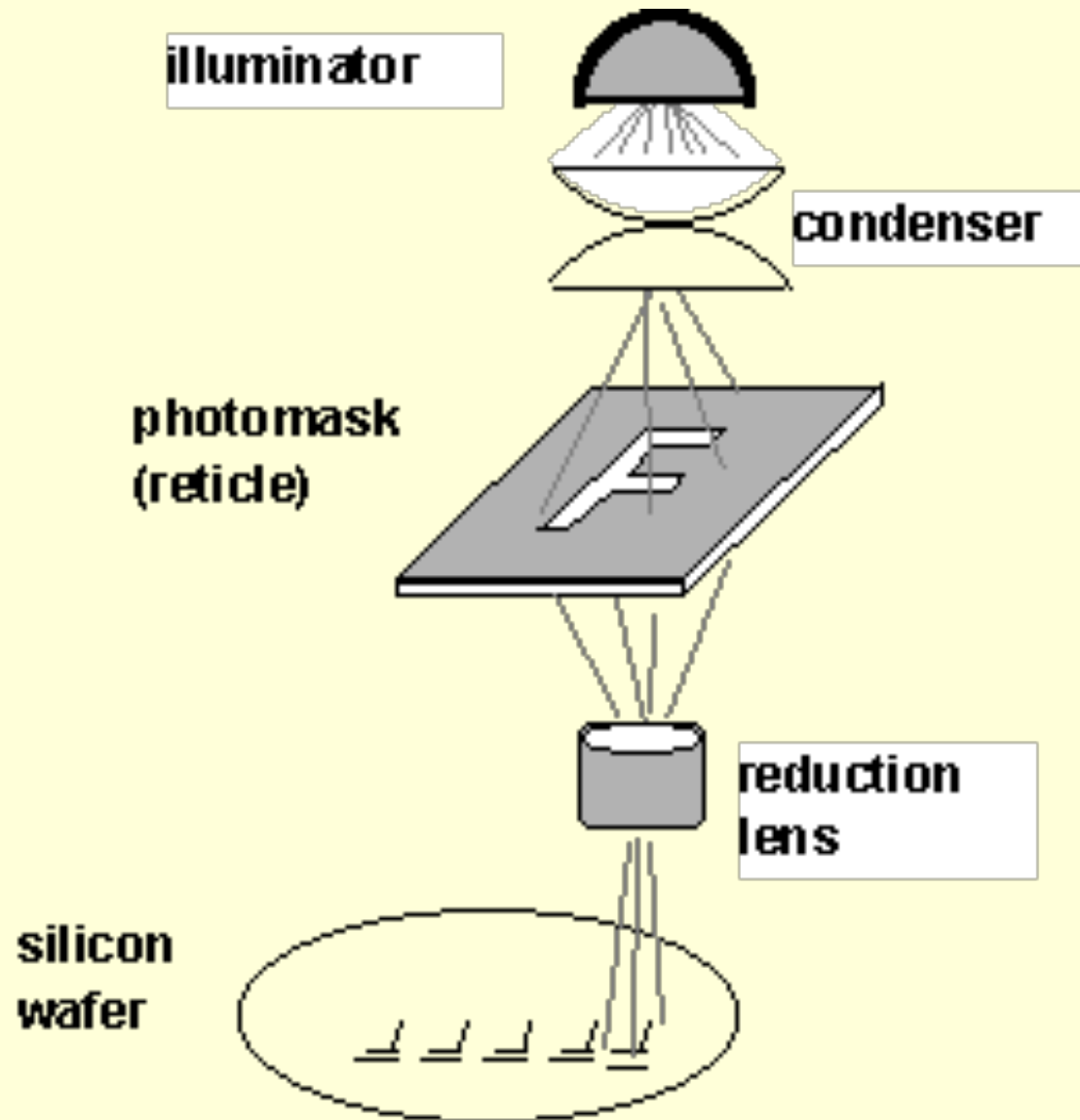


Complicated 3D structures inside a chip



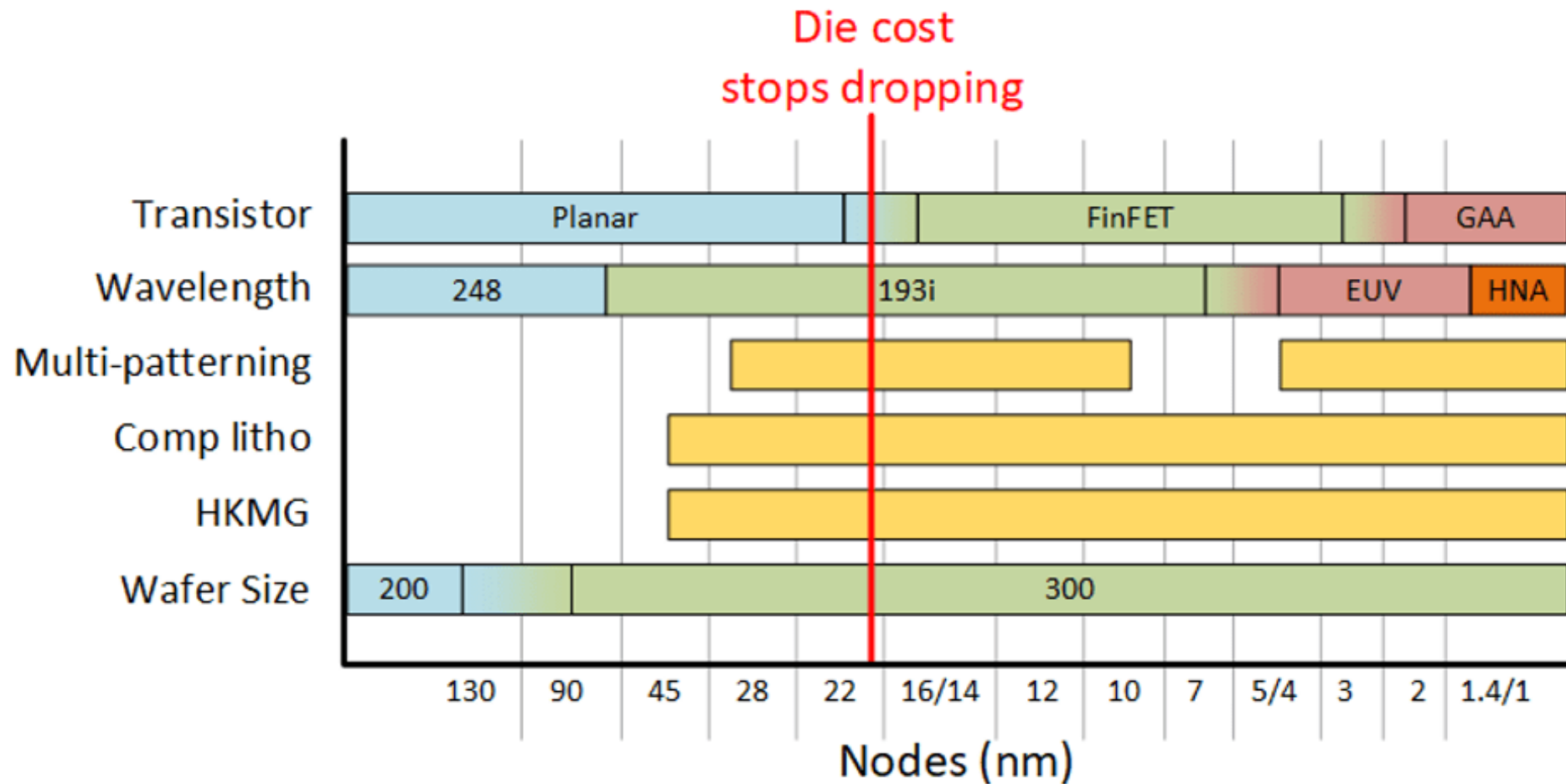
Magnified view: layers of geometric shapes forming complex circuitry

Simplified View of Lithography



But can any arbitrary layout be realized (i.e., lithography-friendly)?

Lithography Development in Last Two Decades



VLSI Design for Manufacturability

- IC fabrication process is imperfect and has various limitations
- Related topics
 - Routing under Nanometer Design Rules
 - Redundant Via Insertion
 - Dummy Fill Insertion
 - Detailed Placement Refinement for Complex Manufacturing Constraints
 - Lithography Hotspot Detection
 - Mask Optimization

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- Leading edge lithography to keep scaling
 - Different kinds of multiple patterning
 - Introduction of EUV
- Related topics
 - Double/Triple Patterning Layout Decomposition
 - Double/Triple Patterning-Aware Routing
 - Double/Triple Patterning-Aware Detailed Placement
 - Self-Aligned Double Patterning Layout Decomposition
 - Self-Aligned Double Patterning-Aware Routing
 - CAD for EUV Lithography

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- Other topics
 - E-beam Direct Write/Mask Writing
 - Optimization with Hybrid Lithography (multiple patterning/DSA/e-beam)

About Instructor

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About TA

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Learning Resources

- Course webpage
 - NTHU eeclass <http://eeclass.nthu.edu.tw/>
 - Lecture notes, assignments will be posted there

Assessment

- Written assignments 40%
- Coding Project 30%
- Exam 30%